

## IRFP460A

## 20A, 500V, 0.22 Ohm, N-Channel SMPS Power MOSFET

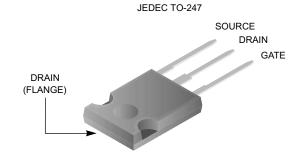
## **Applications**

- Switch Mode Power Supplies (SMPS)
- Uninterruptable Power Supply
- · High Speed Power Switching

### Features

- Low Gate Charge  $Q_g$  results in Simple Drive Requirement
- Improved Gate, Avalanche and Dynamic dv/dt Ruggedness
- Improved r<sub>DS(ON)</sub>
- · Reduced Miller Capacitance

# Package Symbol





## Absolute Maximum Ratings T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units
V <sub>DSS</sub>	Drain to Source Voltage	500	V
V <sub>GS</sub>	Gate to Source Voltage	±30	V
	Drain Current		
	Continuous ( $T_C = 25^{\circ}C$ , $V_{GS} = 10V$ )	20	Α
I <sub>D</sub>	Continuous ( $T_C = 100^{\circ}$ C, $V_{GS} = 10V$ )	13	Α
	Pulsed <sup>1</sup>	80	Α
В	Power dissipation	280	W
$P_{D}$	Derate above 25°C	2.2	W/oC
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature	-55 to 150	°C
	Soldering Temperature for 10 seconds	300 (1.6mm from case)	°C
	Mounting Torque, 8-32 or M3 Screw	10ibf*in (1.1N*m)	

## Thermal Characteristics

$R_{ heta JC}$	Thermal Resistance Junction to Case	0.45	°C/W
$R_{ heta CS}$	Thermal Resistance Case to Sink, Flat, Greased Surface	0.24 TYP	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient	40	°C/W

Markin	g and Ordering Inf	ormation					
Device Marking Device		Package	Reel Size	Tape Width		Quantity	
IRFP460A IRFP460A		TO-247	-	-		-	
Electrical Characteristics T <sub>J</sub> = 25°C (unless otherwise noted)							
	Parameter	Test (	Conditions	Min	Тур	Max	Units
Statics							
Drain to S	ource Breakdown Voltage	$I_D = 250 \mu A$	V <sub>GS</sub> = 0V	500	-	-	V
Breakdown Voltage Temp. Coefficient		V/°C Refere	V/°C Reference to 25°C,		0.61	-	
Drin to So	urce On-Resistance	irce On-Resistance $V_{GS} = 10V, I_D = 12A$		-	0.17	0.22	Ω
Gate Threshold Voltage V <sub>DS</sub> = V <sub>GS</sub> ,		I <sub>D</sub> = 250μA	2.0	3.3	4.0	V	
Zero Gate Voltage Drain Current		V <sub>DS</sub> = 25V	T <sub>C</sub> =25°C	-	-	25	μА
		$V_{GS} = 0V$	$T_{\rm C} = 150^{\rm o}{\rm C}$	-	-	250	μΑ
Gate to So	ource Leakage Current	$V_{GS} = \pm 20V$	,	-	-	±100	nA
Forward Transconductance		V <sub>DS</sub> = 50V,	V <sub>DS</sub> = 50V, I <sub>D</sub> = 12A		-	-	S
Total Gate	Charge	V <sub>GS</sub> = 10V,	V <sub>GS</sub> = 10V,		56	70	nC
Gate to Source Gate Charge		V <sub>DS</sub> = 400V	,	-	13	18	nC
Gate to Dr	ain "Miller" Charge	I <sub>D</sub> = 20A	I <sub>D</sub> = 20A		17	22	nC
Turn-On D	elay Time	$V_{DD} = 250V$	V <sub>DD</sub> = 250V,		13	-	ns
Rise Time		I <sub>D</sub> = 20A		-	8	-	ns
Turn-Off Delay Time		$R_G = 4.3\Omega$		-	41	-	ns
Fall Time		$R_D = 13\Omega$	$R_D = 13\Omega$		6	-	ns
Input Can	acitance		V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0V,		3520	_	pF
Output Cap		\/ 25\/	\/ = 0\/		3320		ы
	Drain to So Breakdown Drin to So Gate Three Zero Gate Gate to So Gate to So Gate to Dr Turn-On D Rise Time Turn-Off D Fall Time	Characteristics T <sub>J</sub> = 25°C (un Parameter  Drain to Source Breakdown Voltage  Breakdown Voltage Temp. Coefficient  Drin to Source On-Resistance  Gate Threshold Voltage  Zero Gate Voltage Drain Current  Gate to Source Leakage Current  Forward Transconductance  Total Gate Charge  Gate to Source Gate Charge  Gate to Drain "Miller" Charge  Turn-On Delay Time  Rise Time  Turn-Off Delay Time	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	arkingDevicePackageReel Size30AIRFP460ATO-247-Characteristics $T_J = 25^{\circ}C$ (unless otherwise noted)ParameterTest ConditionsDrain to Source Breakdown Voltage $I_D = 250\mu A$ , $V_{GS} = 0V$ Breakdown Voltage Temp. Coefficient $V'_C$ Reference to $25^{\circ}C$ , $ID = 1mA$ Drin to Source On-Resistance $V_{GS} = 10V$ , $I_D = 12A$ Gate Threshold Voltage $V_{DS} = V_{GS}$ , $I_D = 250\mu A$ Zero Gate Voltage Drain Current $V_{DS} = 25V$ $V_{GS} = 0V$ $T_C = 25^{\circ}C$ $T_C = 150^{\circ}C$ Gate to Source Leakage Current $V_{DS} = 50V$ , $I_D = 12A$ Forward Transconductance $V_{DS} = 50V$ , $I_D = 12A$ Total Gate Charge $V_{GS} = 10V$ , $V_{DS} = 400V$ , $I_D = 20A$ Gate to Drain "Miller" Charge $I_D = 20A$ Turn-On Delay Time $V_{DD} = 250V$ , $I_D = 20A$ Turn-Off Delay Time $I_D = 20A$ Fall Time $I_D = 13\Omega$	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$

## **Avalanche Characteristics**

E <sub>AS</sub>	Single Pulse Avalanche Energy <sup>2</sup>	960	-	-	mJ
I <sub>AR</sub>	Avalanche Current	-	-	20	Α
E <sub>AR</sub>	Repetitive Avalanche Energy <sup>1</sup>	28	-	-	mJ

### **Drain-Source Diode Characteristics**

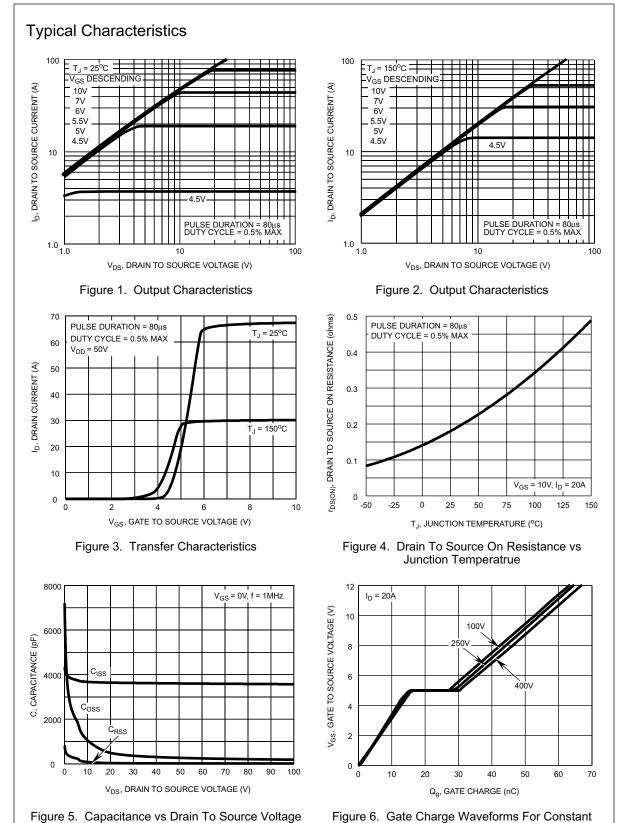
Reverse Transfer Capacitance

Is	Continuous Source Current (Body Diode)	MOSFET symbol showing the integral reverse	-	-	20	Α
I <sub>SM</sub>	Pulsed Source Current <sup>1</sup> (Body Diode)	integral reverse p-n junction diode.	-	-	80	Α
V <sub>SD</sub>	Source to Drain Diode Voltage	I <sub>SD</sub> = 20A	-	0.86	1.8	V
t <sub>rr</sub>	Reverse Recovery Time	$I_{SD} = 20A$ , $dI_{SD}/dt = 100A/\mu s$	-	560	710	ns
$Q_{RR}$	Reverse Recovered Charge	$I_{SD} = 20A$ , $dI_{SD}/dt = 100A/\mu s$	-	8.0	11	μС

- Notes: 
   Repetitive rating; pulse width limited by maximum junction temperature 
   V<sub>DD</sub> = 50V, Starting T<sub>J</sub> = 25°C, L = 7.0mH, R<sub>G</sub> = 25 $\Omega$ , |<sub>AS</sub> = 14A 
   I<sub>SD</sub> </= 14A, di/dt </= 130A/ $\mu$ s, V<sub>DD</sub> </= V<sub>(BR)DSS</sub>, T<sub>J</sub> </= 150°C 
   Pulse width </= 300 $\mu$ s; duty cycle </= 2%

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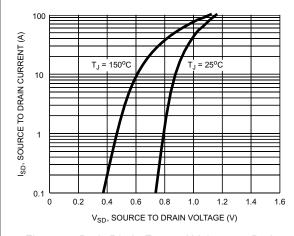
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**Gate Current** 

## Typical Characteristics (Continued)



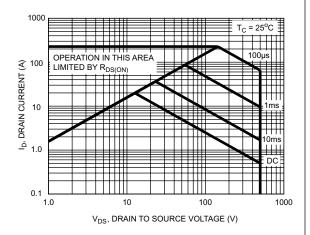


Figure 7. Body Diode Forward Voltage vs Body Diode Current

Figure 8. Maximum Safe Operating Area

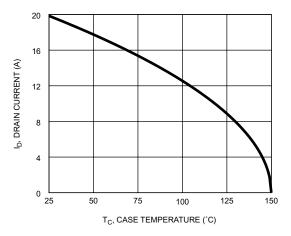


Figure 9. Maximum Drain Current vs Case Temperature

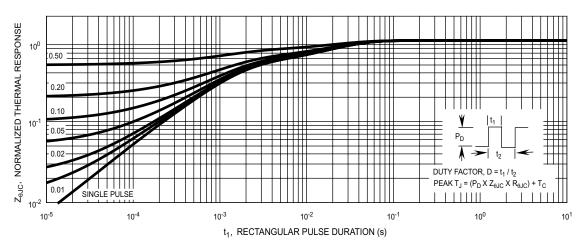


Figure 10. Normalized Transient Thermal Impedance, Junction to Case

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## **Test Circuits and Waveforms**

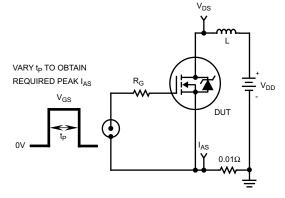


Figure 11. Unclamped Energy Test Circuit

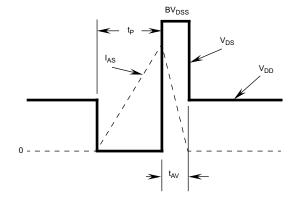


Figure 12. Unclamped Energy Waveforms

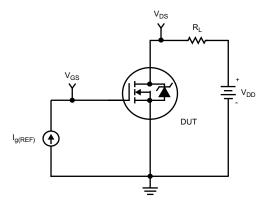


Figure 13. Gate Charge Test Circuit

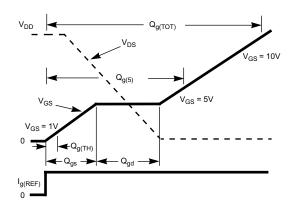


Figure 14. Gate Charge Waveforms

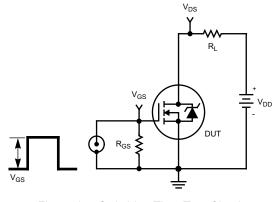


Figure 15. Switching Time Test Circuit

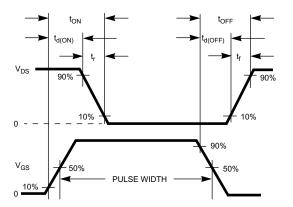


Figure 16. Switching Time Waveform

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